



BSI Standards Publication

Semiconductor devices

Part 1: Time-dependent dielectric breakdown
(TDDB) test for inter-metal layers

NO COPYING WITHOUT BSI PERMISSION EXCEPT AS PERMITTED BY COPYRIGHT LAW

National foreword

This British Standard is the UK implementation of EN 62374-1:2010, incorporating corrigendum April 2011. It is identical to IEC 62374-1:2010.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

© BSI 2011

ISBN 978 0 580 75206 3

ICS 31.080.01

Compliance with a British Standard cannot confer immunity from legal obligations.

This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 December 2010.

Amendments/corrigenda issued since publication

Date	Text affected
30 June 2011	Implementation of CENELEC corrigendum April 2011: supersession details deleted